

Electronic Circuits

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Digital devices

- Introduction
- Gate characteristics
- Logic families
- TTL
- CMOS
- Interfacing
- Noise and EMC in digital systems.

Introduction

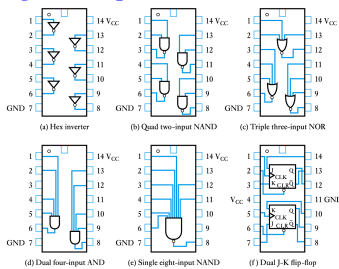
- Earlier we looked at a range of digital applications based on logic gates – at that time we treated the gates as ‘black boxes’.
- We will now consider the construction of such gates, and their characteristics.
- Many terms are used to describe **integration level**.
- In this lecture we will concentrate on **small-** and **medium-scale integration circuits** containing just a handful of gates.

Introduction (contd.)

Integration level	Number of transistors
Zero scale integration (ZSI)	1
Small scale integration (SSI)	2–30
Medium scale integration (MSI)	$30 - 10^3$
Large scale integration (LSI)	$10^3 - 10^5$
Very large scale integration (VLSI)	$10^5 - 10^7$
Ultra large scale integration (ULSI)	$10^7 - 10^9$
Giga-scale integration (GSI)	$10^9 - 10^{11}$
Tera-scale integration (TSI)	$10^{11} - 10^{13}$

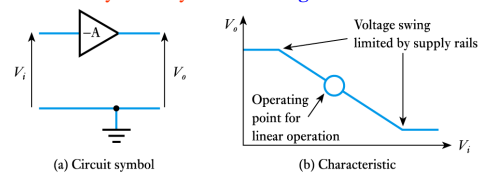
Introduction (contd.)

- **Typical logic device pin-outs.**



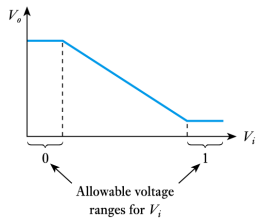
Gate characteristics

- **The inverter or NOT gate**
 - consider the characteristics of a simple inverting amplifier as shown below
 - we normally use only the **linear region**.



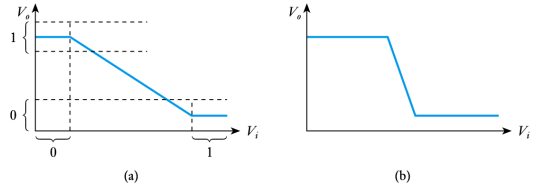
Gate characteristics (contd.)

- We can use an inverting amplifier as a logical inverter but using only the **non-linear** region.



Gate characteristics (contd.)

- We choose input values to ensure that we are always outside of the linear region – as in (a).
- Unlike linear amplifiers, we use circuits with a rapid transition between the non-linear regions – as in (b).



Gate characteristics (contd.)

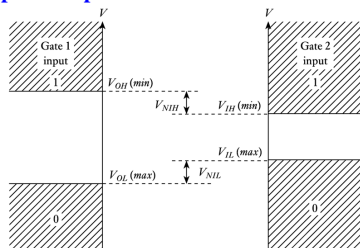
- Logic levels**
 - The voltage ranges representing '0' and '1' represent the **logic levels** of the circuit.
 - Often **logic 0** is represented by a voltage close to 0 V but the allowable voltage range varies considerably.
 - The voltage used to represent **logic 1** also varies greatly. In some circuits it might be 2-4 V, while in others it might be 12-15 V.
 - In order for one gate to work with another the logic levels must be compatible.

Gate characteristics (contd.)

- Noise immunity**
 - Noise is present in all real systems.
 - This adds random fluctuations to voltages representing logic levels.
 - To cope with noise, the voltage ranges defining the logic levels are more tightly constrained at the output of a gate than at the input.
 - Thus small amounts of noise will not affect the circuit.
 - The maximum noise voltage that can be tolerated by a circuit is termed its **noise immunity**, V_{NI} .

Gate characteristics (contd.)

- A graphical representation of noise immunity.**

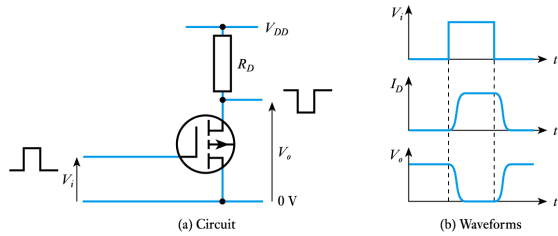


Gate characteristics (contd.)

- Transistors as switches**
 - Both FETs and bipolar transistors make good switches.
 - Neither form produce *ideal* switches and their characteristics are slightly different.
 - Both forms of device take a finite time to switch and this produces a slight delay in the operation of the gate.
 - This is termed the **propagation delay** of the circuit.

Gate characteristics (contd.)

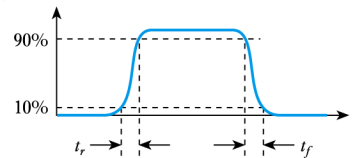
- The FET as a logical switch



Gate characteristics (contd.)

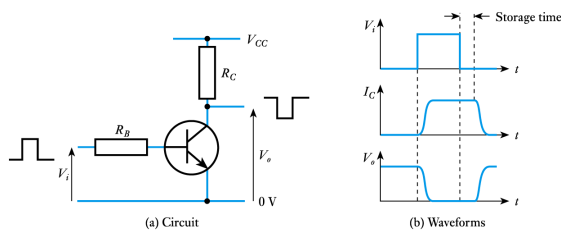
- Rise and fall times

- because the waveforms are not perfectly square we need a way of measuring switching times
- we measure the **rise time, t_r** and **fall time, t_f** as shown below



Gate characteristics (contd.)

- The bipolar transistor as a logical switch



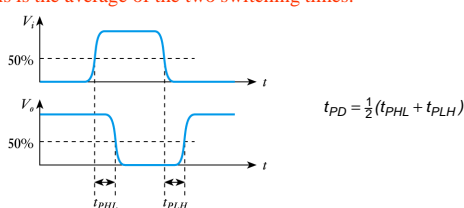
Gate characteristics (contd.)

- When the input voltage to a bipolar transistor is high the transistor turns ON and the output voltage is driven down to its **saturation voltage**, which is about 0.1 V.
- However, saturation of the transistor results in the storage of excess charge in the base region.
- This increases the time taken to turn OFF the device – an effect known as **storage time**.
- This makes the device faster to turn ON than OFF.
- Some switching circuits increase speed by preventing the transistors from entering saturation.

Gate characteristics (contd.)

- Timing considerations

- all gates have a certain **propagation delay time, t_{PD}**
- this is the average of the two switching times.

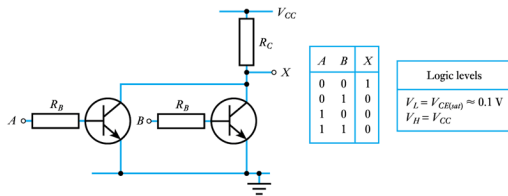


Logic families

- We have seen that different devices use different voltage ranges for their logic levels.
- They also differ in other characteristics.
- In order to assure correct operation when gates are interconnected they are normally produced in families.
- We will look briefly at a range of logic families, then concentrate on the most important ones, namely **TTL** and **CMOS**.

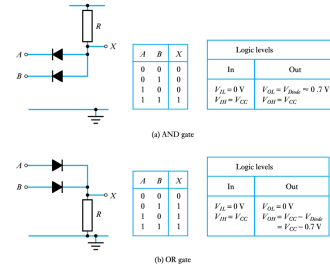
Logic families (contd.)

- Resistor-transistor logic (RTL)
 - an RTL NOR gate



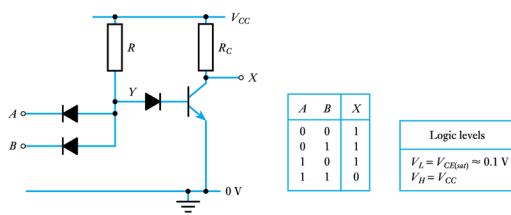
Logic families (contd.)

- Diode logic



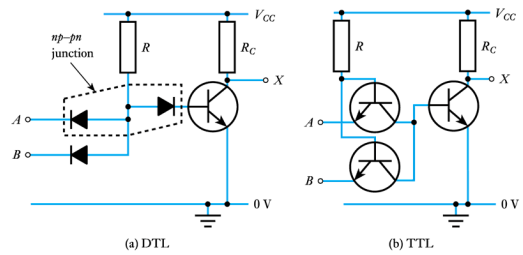
Logic families (contd.)

- Diode-transistor logic
 - A DTL NAND gate



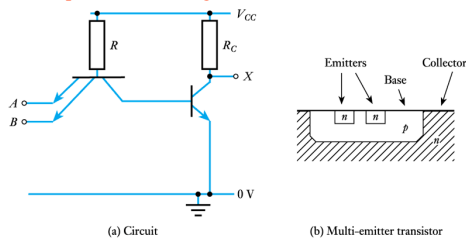
Logic families (contd.)

- Replacing the diodes of a DTL gate with transistors



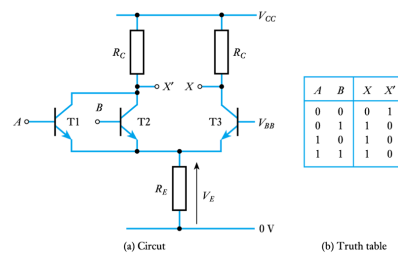
Logic families (contd.)

- Transistor-transistor logic (TTL)
 - a simple TTL NAND gate



Logic families (contd.)

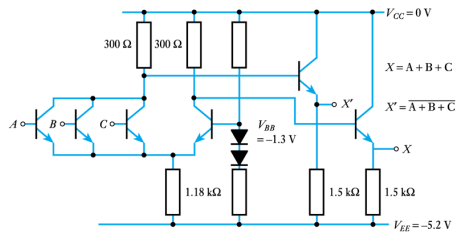
- A non-saturating logic gate.



Logic families (contd.)

- **Emitter-coupled logic (ECL)**

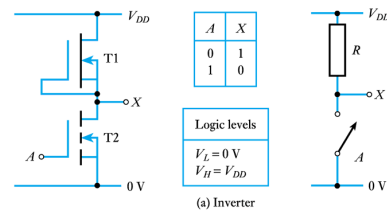
– a three-input ECL OR/NOR gate



Logic families (contd.)

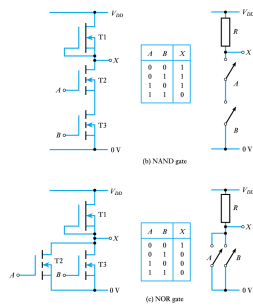
- **Metal oxide semiconductor (MOS) logic**

– NMOS gates



Logic families (contd.)

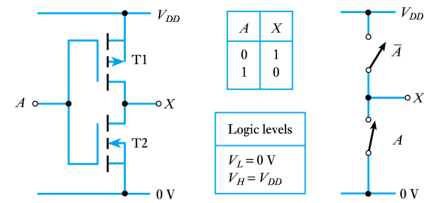
– NMOS NAND and NOR gates



Logic families (contd.)

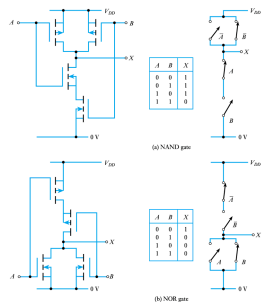
- **Complementary metal oxide semiconductor (CMOS) logic**

– a CMOS inverter



Logic families (contd.)

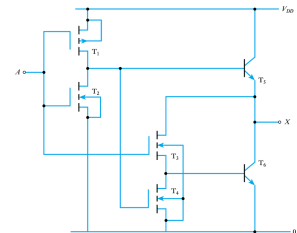
– two-input CMOS gates



Logic families (contd.)

- **Bipolar CMOS (BiCMOS) logic**

– a simple BiCMOS inverter



A comparison of logic families

Parameter	TTL	ECL	CMOS
Basic gate	NAND	OR/NOR	NAND-NOR
Fan-out	10	25	>50
Power per gate (mW)	1 – 22	4 – 55	1 @ 1 MHz
Noise immunity	Very good	Good	Excellent
T_{PD} (ns)	1.5 – 33	1 – 4	1.5 – 200

TTL

- Standard TTL
- part of a typical TTL data sheet

Specification for standard commercial parts

recommended operating conditions

PARAMETER	SN5400			7400			UNIT
	MIN	TYP	MAX	MIN	TYP	MAX	
V_{CC} Supply voltage	4.5	5	5.5	4.75	5	5.25	V
V_{OH} High-level output voltage	2		2				V
V_{OL} Low-level output voltage		0.1		0.1			V
I_{OH} High-level output current			-40			-40	mA
I_{OL} Low-level output current			16			16	mA
T_C Characteristic transition time	10		0			20	ns

electrical characteristics over recommended operating (load) conditions unless otherwise specified

PARAMETER	TEST CONDITIONS ¹			SN5400			7400		
	MIN	TYP	MAX	MIN	TYP	MAX	MIN	TYP	MAX
V_{IH}	$V_{CC} = \text{MIN}, I_C = -12 \text{ mA}$								
V_{OH}	$V_{CC} = \text{MIN}, I_{OH} = -1.5 \text{ mA}, I_{OL} = -0.4 \text{ mA}$	2.4	1.4	2.4	1.4	2.4	1.4	1.4	1.4
V_{OL}	$V_{CC} = \text{MIN}, I_{OH} = -1.5 \text{ mA}, I_{OL} = -0.4 \text{ mA}$		0.2	0.1		0.2	0.1		0.1
I_{OH}	$V_{CC} = \text{MAX}, V_{OL} = 0.1 \text{ V}$								
I_{OL}	$V_{CC} = \text{MAX}, V_{OH} = 2.4 \text{ V}$								
I_{CC}	$V_{CC} = \text{MAX}, V_{OL} = 0.1 \text{ V}$								
I_{DD}	$V_{CC} = \text{MAX}$								
I_{CCQ}	$V_{CC} = \text{MAX}, V_{OL} = 0.1 \text{ V}$								
I_{DDQ}	$V_{CC} = \text{MAX}, V_{OH} = 2.4 \text{ V}$								

Conditions under which values are measured

For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

All typical values are at $V_{CC} = 5 \text{ V}$, $T_C = 25^\circ\text{C}$.

¹ See note 1 on page 10 for test conditions.

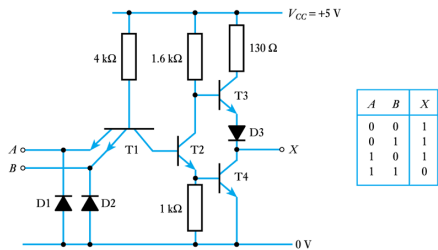
Propagate delay times for different transitions

PARAMETER	FROM	TO	TEST CONDITIONS	MIN			MAX		
				ns	ns	ns	ns	ns	ns
t_{PLH}	A to B	Y	$R_L = 100 \Omega, C_L = 15 \text{ pF}$		11	22		11	22
t_{PHL}	A to B	Y	$R_L = 100 \Omega, C_L = 15 \text{ pF}$		7	15		7	15

NOTE 2: See General Information Section for load circuit and voltage conventions.

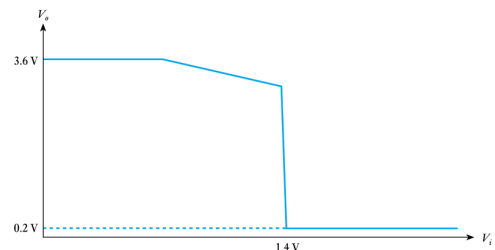
TTL (contd.)

- a TTL two-input NAND gate



TTL (contd.)

- TTL transfer function



TTL (contd.)

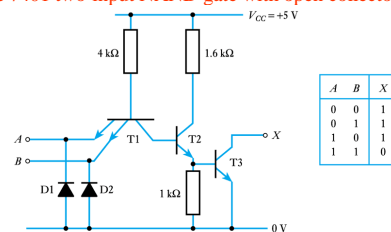
- input and output voltage levels for 74 family devices

	Minimum	Typical	Maximum
V_{IL}	—	—	0.8
V_{IH}	2.0	—	—
V_{OL}	—	0.2	0.4
V_{OH}	2.4	3.6	—

- noise immunity in logic 1 (high) $V_{NIH} = V_{OH(min)} - V_{IH(min)} = 2.4 - 2.0 = 0.4 \text{ V}$
- noise immunity in logic 0 (low) $V_{NIL} = V_{IL(max)} - V_{OL(max)} = 0.8 - 0.4 = 0.4 \text{ V}$

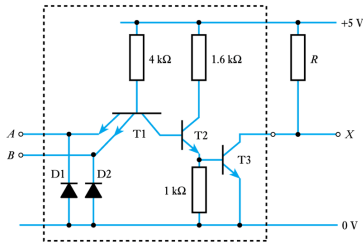
TTL (contd.)

- Open collector devices
- the 7401 two-input NAND gate with open collector output.



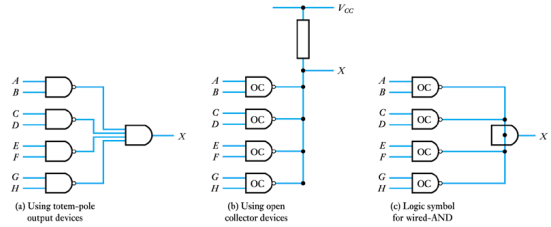
TTL (contd.)

- use of an open collector gate with an external load



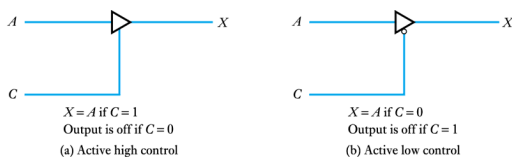
TTL (contd.)

- **Wired-AND operation**



TTL (contd.)

- **Three-state outputs**



TTL (contd.)

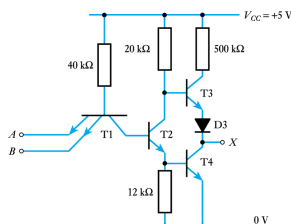
- **TTL inputs**

- unused inputs, if left unconnected, will float to logic 1
- it is inadvisable to allow them to float since they are then very susceptible to noise
- unused inputs should be tied to ground (logic 0) or through a resistor to the positive supply rail (logic 1)
 - unused inputs to an AND or NAND gate should be tied *high*
 - unused inputs to an OR or NOR gate should be tied *low*.

Other TTL families

- **Low-power TTL (74L)**

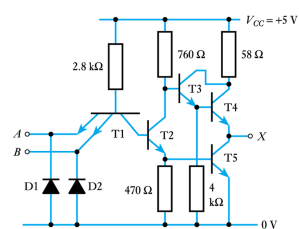
- a 74L00 two-input NAND gate



Other TTL families (contd.)

- **High-speed TTL (74H)**

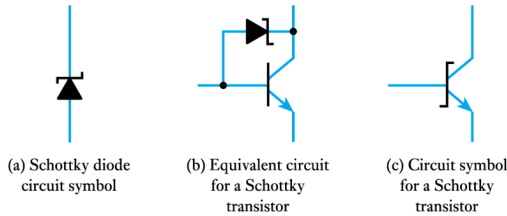
- a 74H00 two-input NAND gate



Other TTL families (contd.)

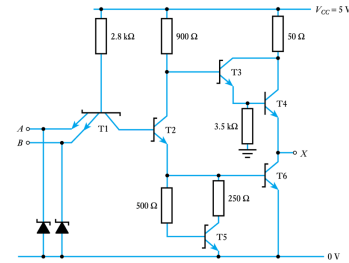
- **Schottky TTL (74S)**

– Schottky diodes and transistors



Other TTL families (contd.)

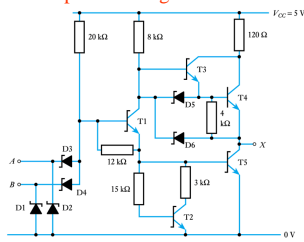
– a 74S00 two-input NAND gate



Other TTL families (contd.)

- **Low-power Schottky TTL (74LS)**

– a 74LS00 two-input NAND gate



A comparison of TTL families

Family	Descriptor	T_{PD} (ns)	Power per gate (mW)
Standard	74XX	9	10
Low-power	74LXX	33	1
High-speed	74HXX	6	22
Schottky	74SXX	3	19
Advanced Schottky	74ASXX	1.5	8.5
Low-power Schottky	74LSXX	9.5	2
Advanced low-power Schottky	74ALSXX	4	1
FAST	74FXX	2.7	4

CMOS

- **CMOS**

– part of a typical CMOS data sheet

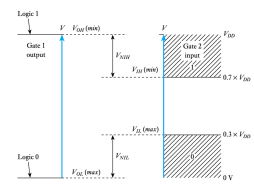
Electrical characteristics (typical values unless otherwise specified)

Supply voltage, V_{CC} 4.5 V to 15 V
 Input current, I_{IH} (at $V_{IH} = 0.7 \times V_{CC}$) 100 nA
 Output current, I_{OH} (at $V_{OL} = 0.3 \times V_{CC}$) 40 mA
 Output current, I_{OL} (at $V_{OL} = 0.3 \times V_{CC}$) 40 mA
 Propagation delay, t_{PD} (at $V_{CC} = 5V$) 10 ns
 Load capacitance, C_L (at $V_{CC} = 5V$) 50 pF
 Load capacitance, C_L (at $V_{CC} = 15V$) 100 pF
 Input resistance, R_{in} (at $V_{IH} = 0.7 \times V_{CC}$) 100 MΩ
 Input resistance, R_{in} (at $V_{IH} = 0.3 \times V_{CC}$) 100 MΩ
 Output resistance, R_{out} (at $V_{OH} = 0.7 \times V_{CC}$) 100 Ω
 Output resistance, R_{out} (at $V_{OL} = 0.3 \times V_{CC}$) 100 Ω
 Static power dissipation, P_{static} (at $V_{CC} = 5V$) 100 nW
 Dynamic power dissipation, $P_{dynamic}$ (at $V_{CC} = 5V$) 100 nW

PARAMETER	TYPICAL		MINIMUM		MAXIMUM		UNIT
	$V_{CC} = 5V$	$V_{CC} = 15V$	$V_{CC} = 5V$	$V_{CC} = 15V$	$V_{CC} = 5V$	$V_{CC} = 15V$	
V_{OH}	2.4	10	2.0	10	2.4	10	V
	2.0	10	1.5	10	2.0	10	V
V_{OL}	0.1	0.1	0.1	0.1	0.1	0.1	V
	0.1	0.1	0.1	0.1	0.1	0.1	V
t_{PD}	10	10	10	10	10	10	ns
	10	10	10	10	10	10	ns
P_{static}	100	100	100	100	100	100	nW
	100	100	100	100	100	100	nW
$P_{dynamic}$	100	100	100	100	100	100	nW
	100	100	100	100	100	100	nW
R_{in}	100	100	100	100	100	100	MΩ
	100	100	100	100	100	100	MΩ
R_{out}	100	100	100	100	100	100	Ω
	100	100	100	100	100	100	Ω

CMOS (contd.)

– CMOS input and output voltage levels



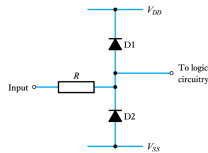
– noise immunity in logic 1 (high) $V_{NIH} = V_{OH(min)} - V_{IH(min)} = V_{DD} - 0.7 \times V_{DD} = 0.3 \times V_{DD}$

– noise immunity in logic 0 (low) $V_{NIL} = V_{IL(max)} - V_{OL(max)} = 0.3 \times V_{DD} - 0 = 0.3 \times V_{DD}$

CMOS (contd.)

- **CMOS inputs**

- CMOS gate protection circuitry



- CMOS inputs must *not* be left unconnected
- unused inputs should be tied to ground (logic 0) or to the positive supply rail (logic 1)
 - unused inputs to an AND or NAND gate should be tied *high*
 - unused inputs to an OR or NOR gate should be tied *low*.

CMOS (contd.)

- **CMOS outputs**

- typical output resistance of about 250Ω (5V operation)
- high input resistance produces a high fan-out
- propagation delay increases with the number of gates being driven
- if high-speed operation is not required, at least 50 gates can be driven from a single output
- no CMOS equivalent of open-collector output
- some CMOS gates have three-state facility.

CMOS families

- **Standard CMOS (4000B)**

- one of the oldest form of CMOS – now largely obsolete
- operates with supply voltages of 3-18 V
- can produce very high noise immunity (typically about $0.45 \times V_{CC}$)
- relatively slow – propagation delay times of 45–125 ns.

CMOS families (contd.)

- **Standard CMOS with TTL pin-out (74C)**

- adopts a device numbering scheme compatible with corresponding TTL parts
- operates with supply voltages of 3–18 V
- can produce very high noise immunity (typically about $0.45 \times V_{CC}$)
- relatively slow – propagation delay times of 30–50 ns.

CMOS families (contd.)

- **High-speed CMOS (74HC)**

- will operate with supply voltages of 2–6 V, but often uses a 5 V supply
- significantly faster than standard CMOS ($T_{PD} \approx 8\text{ns}$)

- **High-speed CMOS, TTL compatible inputs (74HCT)**

- another high-speed family, which offers TTL compatible inputs
- operates with supply voltages of 4.5–5.5 V
- direct replacements for similar TTL parts, with similar speeds to 74LS parts.

CMOS families (contd.)

- **Advanced CMOS (74AC)**

- offer a significant speed advantage over high-speed CMOS ($T_{PD} \approx 4\text{ns}$), with similar power consumption
- will operate with supply voltages of 2–6 V

- **Advanced CMOS, TTL compatible inputs (74ACT)**

- offers similar performance to Advanced CMOS, but has TTL compatible inputs
- operates with supply voltages of 4.5–5.5 V.

CMOS families (contd.)

- **Low-voltage CMOS (74LV)**
 - can be used with supply voltages of 2 – 5.5 V, permitting low voltage operation where necessary
- **Advanced, low-voltage CMOS (74ALVC)**
 - this advanced low-voltage family can be used with supply voltages between 1.65 and 3.6 V
 - provides considerable speed advantage compared to the 74LV series
 - T_{PD} might be 3 ns when used with a supply voltage of 3.0 V, increasing to 4.4 ns when used at 1.8 V.

CMOS families (contd.)

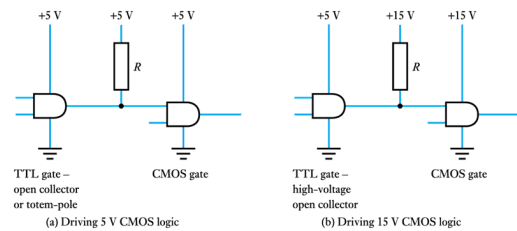
- **BiCMOS (74BCT)**
 - provides a range of high-speed input/output and device driver circuits
 - normally used with a supply voltage of 5 V, but will accept supply voltages in the range 4.5 – 5.5 V
 - typical T_{PD} about 3–4 ns.
- **Low-voltage BiCMOS (74LVT)**
 - offers BiCMOS operation in a family that can be used with supply voltages between 2.7 and 3.6 V.

A comparison of CMOS families

Family	Descriptor	T_{PD} (ns)	Static power per gate (μ W)
Standard	4000B	75	50
Standard, TTL pin-out	74CXX	50	50
High-speed	74HCXX	8	25
High-speed, TTL compatible	74HCTXX	12	25
Advanced	74ACXX	4	25
Advanced, TTL compatible	74ACTXX	6	25
Low-voltage	74LVXX	9	50
Advanced, low-voltage	74ALVCXX	3	50
BiCMOS	74BCTXX	3.5	600
Low-voltage BiCMOS	74LVTXX	4	400

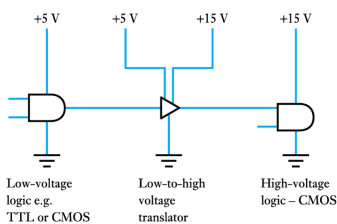
Interfacing TTL and CMOS

- **Driving CMOS from TTL**



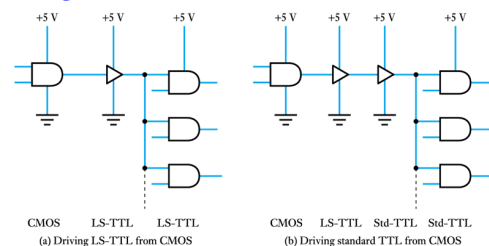
Interfacing TTL and CMOS (contd.)

- use of a low-to-high voltage translator



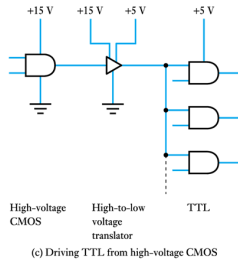
Interfacing TTL and CMOS (contd.)

- **Driving TTL from CMOS**



Interfacing TTL and CMOS (contd.)

– using a high-to-low voltage translator

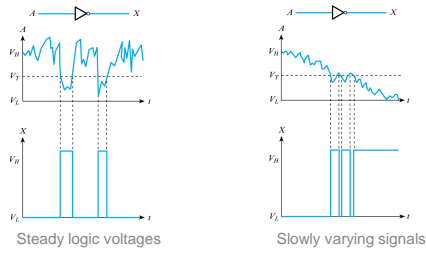


Noise and EMC in digital systems

- Digital noise sources
 - Electronic noise
 - Interference
 - Internal noise
 - Power supply noise
 - CMOS switching transients.

Noise and EMC in digital systems (contd.)

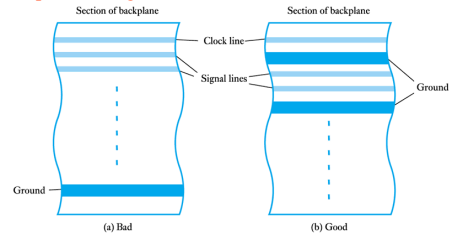
• The effects of noise in digital systems



Noise and EMC in digital systems (contd.)

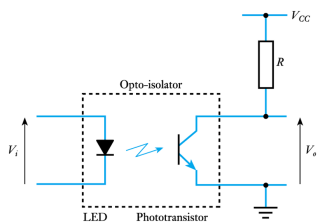
• Designing digital systems for EMC

– backplane arrangements



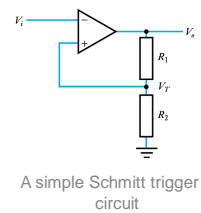
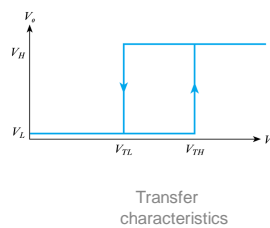
Noise and EMC in digital systems (contd.)

– opto-isolation



Noise and EMC in digital systems (contd.)

– Schmitt trigger inputs



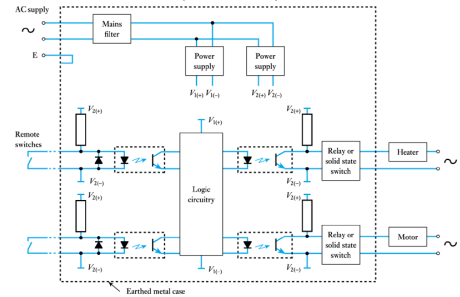
Noise and EMC in digital systems (contd.)

▪ A design example

An industrial control system

A system is connected to **two remote mechanical switches**, and to an **AC heater** and an **AC motor**. The controller is required to take signals from the switches and to turn the heater and motor ON and OFF according to some control algorithm. The system is to be used in an environment with a **high level of electrical noise**. Suggest how the unit could be designed to minimize the effects of noise on its operation.

Noise and EMC in digital systems (contd.)



Key points

- Physical gates are not ideal components.
- Logic gates are manufactured in a range of logic families.
- The ability of a gate to ignore noise is its 'noise immunity'.
- Both MOSFETs and bipolar transistors are used in gates.
- All logic gates exhibit a propagation delay.
- The most widely used logic families are TTL and CMOS.
- Both TTL and CMOS gates are produced in a range of versions, each optimised for a particular characteristic.
- Interface circuitry may be needed to link devices of different families.
- Noise and EMC issues must be considered during design.